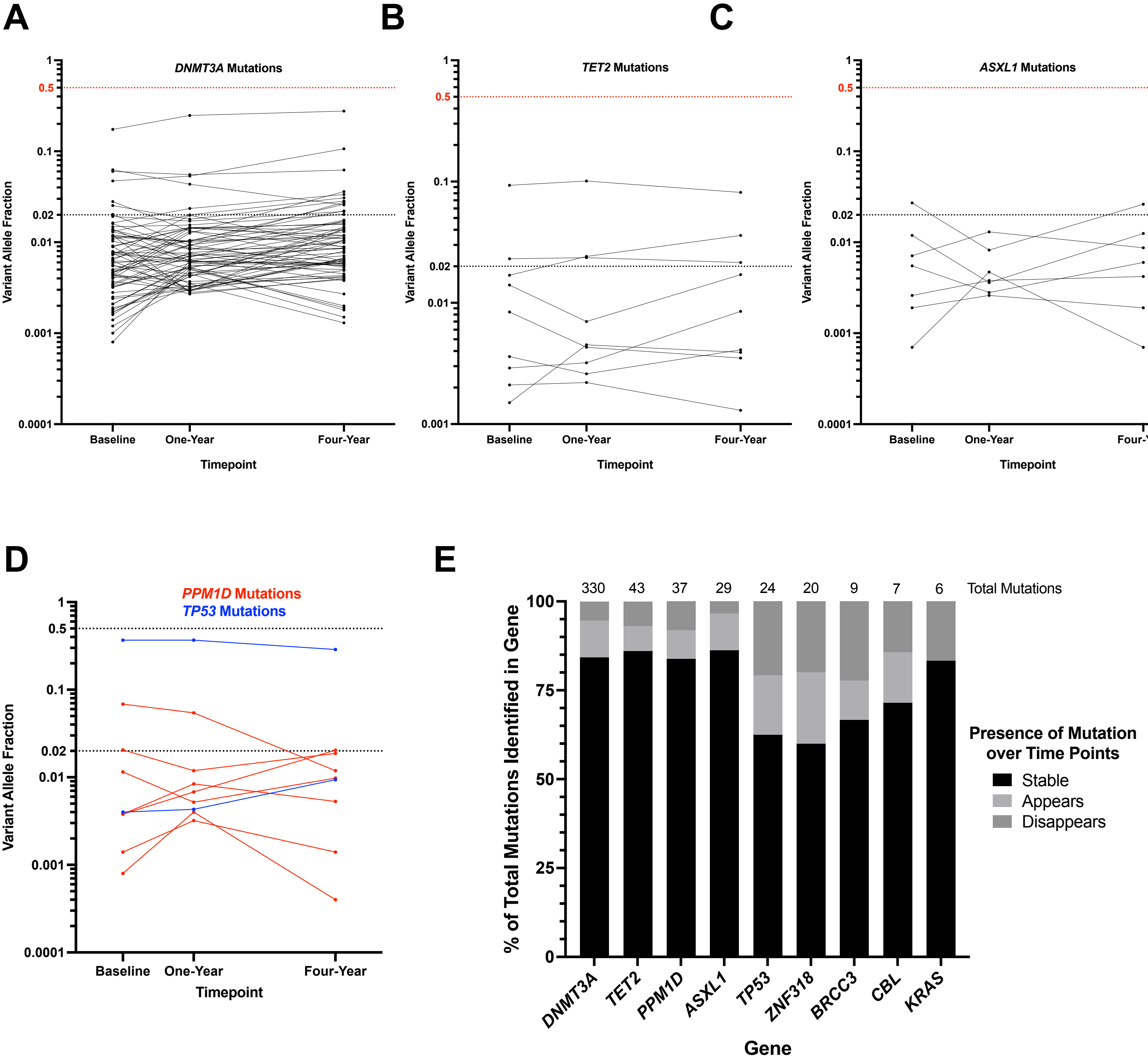

Supplemental Figure S3: Longitudinal Mutation Analysis in the YWS.

(A-D) Change in variant allele fraction (VAF) for mutations stratified by gene identified in patients with sequencing data from three time points. The horizontal dashed line at VAF 0.02 reflects the cutoff for CHIP.
(E) Frequency of mutations in based on presence or absence at different time point.
Note that mutations presented are only in genes assessed on both of the sequencing panels used at the different time points (see Supplemental Tables S1 and S2).